



**ANSI/EIA-364-25E-2017**  
**Approved: March 28, 2017**

**EIA-364-25E**

# **EIA STANDARD**

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## **TP-25E**

### **Probe Damage Test Procedure for Electrical Connectors**

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## **EIA-364-25E** (Revision of EIA-364-25D)

**March 2017**

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**Electronic Components Industry Association**

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(From Standards Proposal No. 5373.02 formulated under the cognizance of the CE-2.0 Committee on EIA National Connector and Sockets Standards.)

Published by

©Electronic Components Industry Association 2017  
EIA Standards & Technology Department  
2214 Rock Hill Road, Suite 265  
Herndon, VA 20170

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